Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/706,288	KURIHARA ET AL.	
Examiner	Art Unit	
Nguyen T. Ha	2831	

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Class	Subclass	Date	Examiner
361	306.3	2/2/05	WH
	306.1		
	301.1		
,	301.2		
	3.03		
	311		
	313		
	321.1		
	321.2		
	321.5		
157	532		
	295		
	296		
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INI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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